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Tech Tours : An Educational Series

Industry Speakers

10:00 a.m.

'Confocal Microscopy & Toolmark Analysis:
Pushing out the Frontiers of Forensic Science'

Nicholas Petraco, Ph.D., Associate Professor

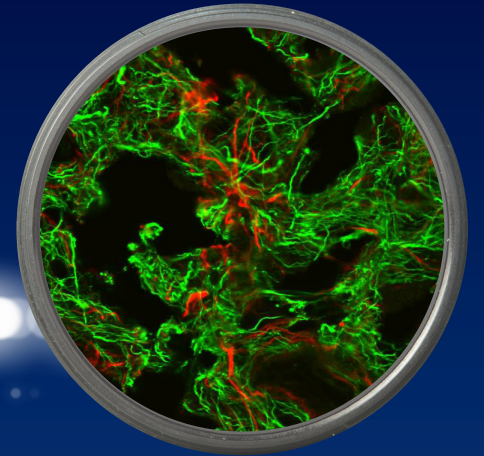
John Jay College of Criminal Justice

1:30 p.m.

Finding Order in Chaos: Surface Metrology for
Discriminating Surface Textures'

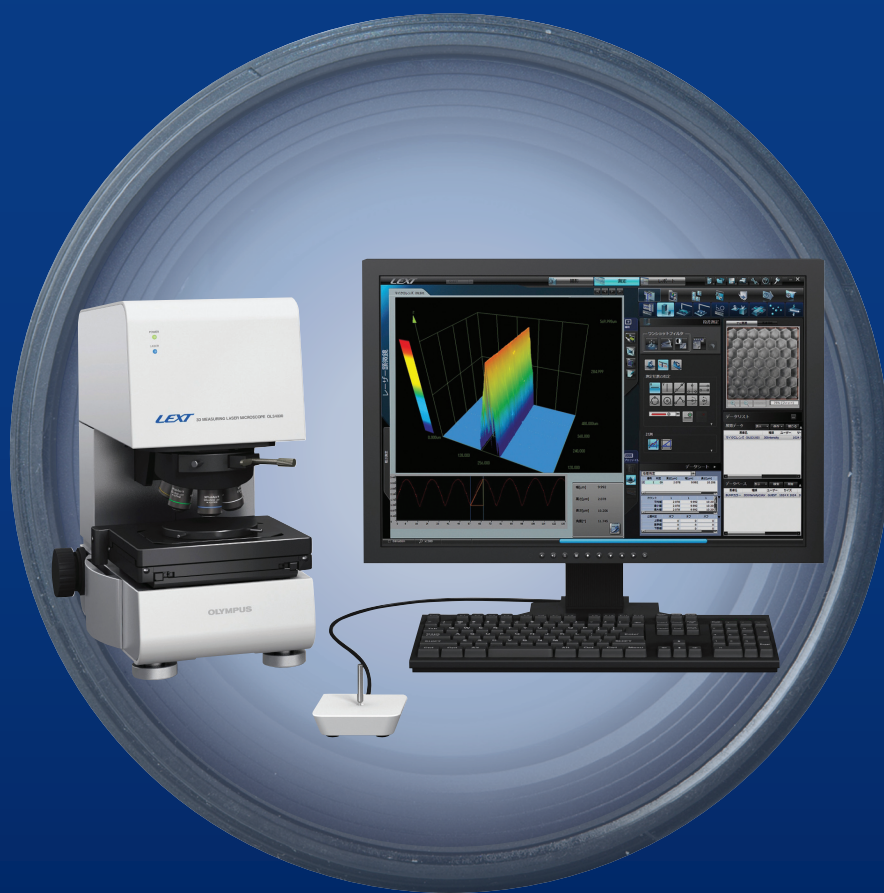
Christopher Brown, Ph.D., Surface Metrology Laboratory

Mechanical Engineering, WPI



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please visit the Tech Tours
website or contact:

Chuck Donelson for Materials Research

Email: charles.donelson@olympus.com

Phone: 203-233-1622

-Or-

Marty Eber for Biomedical Research

Email: martin.eber@olympus.com

Phone: 201-803-9289

Bring samples, ask questions, capture images,
measure, analyze, and investigate!

Location: John Jay College of Criminal Justice (CUNY)
555 West 57th Street, Room 616

September 21st, 8:30 a.m. - 5:00 p.m.

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